

QUERY CONTROL FORM			RTIS USE ONLY		
Application No.	<u>10/644,926</u>	Prepared by	<u>BSH</u>	Tracking Number	<u>05940563</u>
Examiner-GAU	<u>Pekt-2829</u>	Date	<u>06-02-04</u>	Week Date	<u>04-26-2004</u>
		No. of queries	<u>1</u>		<u>IFW RU7</u>

**JACKET**

- |                      |                        |                    |                |
|----------------------|------------------------|--------------------|----------------|
| a. Serial No.        | f. Foreign Priority    | k. Print Claim(s)  | p. PTO-1449    |
| b. Applicant(s)      | g. Disclaimer          | l. Print Fig.      | q. PTOL-85b    |
| c. Continuing Data   | h. Microfiche Appendix | m. Searched Column | r. Abstract    |
| d. PCT               | i. Title               | n. PTO-270/328     | s. Sheets/Figs |
| e. Domestic Priority | j. Claims Allowed      | o. PTO-892         | t. Other       |

**SPECIFICATION**

- a. Page Missing
- b. Text Continuity
- c. Holes through Data
- d. Other Missing Text
- e. Illegible Text
- f. Duplicate Text
- g. Brief Description
- h. Sequence Listing
- i. Appendix
- j. Amendments
- k. Other

**MESSAGE**

Please either initial or line through citations. Copy provided for reference,

**CLAIMS**

- a. Claim(s) Missing
- b. Improper Dependency
- c. Duplicate Numbers
- d. Incorrect Numbering
- e. Index Disagrees
- f. Punctuation
- g. Amendments
- h. Bracketing
- i. Missing Text
- j. Duplicate Text
- k. Other

Thank you

initials BSH

**RESPONSE**

initials

Form PTO-1449 (Rev. 8-83)		U.S. Department of Commerce Patent and Trademark Office		Docket No. 740756-2406		Serial No. Not Yet Assigned
<b>INFORMATION DISCLOSURE STATEMENT</b>						
(Use several sheets if necessary)						
				Applicant: Shunpei YAMAZAKI et al.		
				Filing Date: January 15, 2002 Group: 2813		
<b>U.S. PATENT DOCUMENTS</b>						
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)
	5,648,277	07/15/1997	Zhang et al.			
	5,643,826	07/01/1997	Ohtani et al.			
	6,124,154	09/26/2000	Miyasaka			
	5,550,070	08/27/1996	Funai et al.			
<b>FOREIGN PATENT DOCUMENTS</b>						
	Document Number	Date	Country	Class	Subclass	Translation Yes N
	08-078329	03/22/1996	Japan			Abstract
	07-321339	12/08/1995	Japan			Abstract
	07-130652	05/19/1995	Japan			Abstract
	07-135318	05/23/1995	Japan			Abstract
	05-109737	04/30/1993	Japan			
<b>OTHER DOCUMENTS</b> (Including Author, Title, Date, Pertinent Pages, Etc.)						
	R. Shimokawa and Y. Hayashi, "Characterization of High-Efficiency Cast-Si Solar Cell Wafers by MBIC Measuremant", Japanese Journal of Applied Physics, Vol. 27, No. 5, May, 1988, pp. 751-758					
<b>Examiner</b>	<b>Date Considered</b>					
*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.						